


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,855	CHANG, SUNG-SAN	
	Examiner	Art Unit	
	Henok G. Heyi	2627	

SEARCHED			
Class	Subclass	Date	Examiner
369	30.27	10/23/2007	HH
369	53.25	10/23/2007	HH
720	600	10/23/2007	HH
720	601	10/23/2007	HH
720	602	10/23/2007	HH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Searched EAST and google patents. Consulted Primary Tan Dinh and Krista Bui.	10/23/2007	HH